

**Project Report for the
New York State Snap Bean Research Association**

Title: Refining methods for predicting European corn borer problems in snap beans

Funding Period and Amount Requested: 3/1/98 - 12/31/98 \$2780

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Background:

European corn borer contamination of processing snap beans is a periodic problem in New York. While this pest has a negligible effect on yield, extremely low tolerances for ECB contamination in raw product at the processing plant has required that infested acres be bypassed in some years, resulting in significant economic losses. Existing recommendations for monitoring and controlling this pest do not provide a systematic method for determining which fields are most at risk of ECB contamination.

Over the past two growing seasons we have collected information on ECB populations in snap beans through field scouting and monitoring moth flights. We have used a participatory approach designed to involve researchers, Extension field staff, growers, processors, and consultants. This approach has greatly strengthened the project, since these stakeholders have provided information, support, insight, and appropriate direction to the project.

For a printed copy of the entire report, please contact the NYS IPM office at:

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